Emerging Trends and Challenges in IoT Networks

Guest Editors:

Prof. Dr. Hosung Park
Department of Cyber Security and Police, Busan University of Foreign Studies, Busan 46234, Korea

Prof. Dr. Soochang Park
Department of Computer Engineering, Chungbuk National University, Chungbuk 28644, Korea

Message from the Guest Editors

This Special Issue aims to bring together academic and industrial researchers in sharing their views and ideas concerning emerging trends and challenges in IoT networks. Topics include, but are not limited to, the following areas:

- Near-future technologies, requirements, and challenges of IoT networks;
- Promising models, protocols, management, and architecture for IoT networks;
- Cyber-physical applications over IoT networks;
- Quality of service and experience for IoT networks;
- Age of data issues for IoT networks;
- Knowledge discovery and acquisition for IoT networks;
- Machine learning for IoT networks;
- Edge AI for IoT networks;
- Security and privacy in IoT networks;
- Green IoT networks;
- Self-sustainable IoT networks;
- Industrial IoT networks.

Special Issue

Editor-in-Chief

Prof. Dr. Flavio Canavero
Department of Electronics and
Telecommunications,
Politecnico di Torino, 10129
Torino, Italy

Message from the Editor-in-Chief

Electronics is a multidisciplinary journal designed to appeal to a diverse audience of research scientists, practitioners, and developers in academia and industry. The journal is devoted to fast publication of latest technological breakthroughs, cutting-edge developments, and timely reviews of current and emerging technologies related to the broad field of electronics. Experimental and theoretical results are published as regular peer-reviewed articles or as articles within Special Issues guest-edited by leading experts in selected topics of interest.

Author Benefits

Open Access: free for readers, with article processing charges (APC) paid by authors or their institutions.
High Visibility: indexed within Scopus, SCIE (Web of Science), CAPlus / SciFinder, Inspec, and other databases.
Journal Rank: JCR - Q2(*Electrical and Electronic Engineering*) CiteScore - Q2 (*Electrical and Electronic Engineering*)

Contact Us